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(54) **An X-ray diffraction method of mapping grain structures in a crystalline material sample, and an X-ray diffraction apparatus.**

Röntgenstrahlbrechungsverfahren zum Abbilden von Kornstrukturen in einer kristallinen Materialprobe und Röntgenstrahlbrechungsanordnung

Procédé de mise en correspondance de structures de grain par diffraction des rayons X dans un échantillon de matériau cristallin et appareil de diffraction des rayons X

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